

Analysis and improvement of resilience for long short-term memory neural networks

Ahmadilivani, Mohammad Hasan; Raik, Jaan; Daneshtalab, Masoud; Kuusik, Alar 2023 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT) 2023 / 4 p <https://doi.org/10.1109/DFT59622.2023.10313559>

Bidirectional solid-state DC circuit breaker for the protection of residential and Commercial DC buildings

Aditya, P.; Yagna, V.; Banoth, T.; Chub, Andrii; Banavath, Satish Naik 2023 IEEE 8th Southern Power Electronics Conference and 17th Brazilian Power Electronics Conference (SPEC/COBEP) 2023 / 6 p <https://doi.org/10.1109/SPEC56436.2023.10407460>

Comparison of (N+1) redundancy and fault tolerance approaches in single-stage series-connected isolated MVAC to LVDC converters

Bakeer, Abualkasim Ahmed Ali; Chub, Andrii; Blinov, Andrei; Bayhan, Sertac; Vinnikov, Dmitri 2023 International Conference on Clean Electrical Power (ICCEP) 2023 / p. 469-474 : ill <https://doi.org/10.1109/ICCEP57914.2023.10247478>

DeepVigor+: Scalable and Accurate Semi-Analytical Fault Resilience Analysis for Deep Neural Networks

Ahmadilivani, Mohammad Hasan; Raik, Jaan; Daneshtalab, Masoud; Jenihhin, Maksim arXiv.org 2024 / 14 p. : ill <https://doi.org/10.48550/arXiv.2410.15742>

Design methodology for fault-tolerant heterogeneous MPSoC under real-time constraints

Amin, Mohsin; Tagel, Mihkel; Jervan, Gert; Hollstein, Thomas 7th International Workshop on Reconfigurable and Communication-Centric Systems-on-Chip : July 9-11, 2012 : York, United Kingdom : proceedings 2012 / [6 p.] : ill <https://ieeexplore.ieee.org/document/6322901>

How to prove that a circuit is fault-free?

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings : 15th Euromicro Conference on Digital System Design DSD 2012 : 5-8 September 2012, Cesme, Izmir, Turkey 2012 / p. 427-430 : ill https://www.researchgate.net/publication/262271409_How_to_Prove_that_a_Circuit_is_Fault-Free

On-chip sensors data collection and analysis for SoC health management

Shibin, Konstantin; Jenihhin, Maksim; Jutman, Artur; Devadze, Sergei; Tsertov, Anton 2023 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT) 2023 / 6 p <https://doi.org/10.1109/DFT59622.2023.10313562>

ProAct: Progressive Training for Hybrid Clipped Activation Function to Enhance Resilience of DNNs

Mousavi, Seyedhamidreza; Ahmadilivani, Mohammad Hasan; Raik, Jaan; Jenihhin, Maksim; Daneshtalab, Masoud arXiv.org 2024 / 12 p. : ill <https://doi.org/10.48550/arXiv.2406.06313>

Representing gate-level SET faults by multiple SEU faults on RT-level

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Ubar, Raimund-Johannes; Sauer, Christian 2020 IEEE 26th International Symposium on On-Line Testing and Robust System Design (IOLTS), 13-15 July 2020 : proceedings 2020 / art. 19889351, 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159715>

RESCUE: interdependent challenges of reliability, security and quality in nanoelectronic systems

Jenihhin, Maksim; Raik, Jaan 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2020 / art. 19690741, 6 p <https://doi.org/10.23919/DATE48585.2020.9116558>

Short-circuit fault detection and remedial in full-bridge rectifier of series resonant DC-DC converter based on inductor voltage signature

Bakeer, Abualkasim Ahmed Ali; Chub, Andrii; Vinnikov, Dmitri 2020 IEEE 61st International Scientific Conference on Power and Electrical Engineering of Riga Technical University (RTUCON), Riga, Latvia, Nov. 5-7, 2020 : conference proceedings 2020 / 6 p. : ill <https://doi.org/10.1109/RTUCON51174.2020.9316482>

Tehissüsteemide veakindlusest : [TTÜ arvutitehnika instituudi teadustöödest]

Ubar, Raimund-Johannes Horisont 2006 / 2, lk. 64-69 : ill https://artiklid.elnet.ee/record=b2039558*est

Understanding fault-tolerance vulnerabilities in advanced SoC FPGAs for critical applications

Cherezova, Natalia; Shibin, Konstantin; Jenihhin, Maksim; Jutman, Artur Microelectronics reliability 2023 / art. 115010, 10 p. : ill <https://doi.org/10.1016/j.microrel.2023.115010> Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Usaldusväärsus ja veakindlus infohankesüsteemides

Mürsepp, Ivo A & A 2011 / 2, lk. 28-46 : ill